

FDR836P

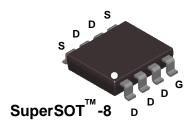
P-Channel 2.5V Specified MOSFET

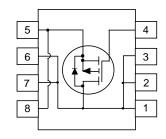
General Description

SuperSOTTM -8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as battery powered circuits or portable electronics where low in-line power loss, fast switching and resistance to transients are needed.

Features

- -6.1 A, -20 V. $R_{DS(ON)} = 0.030 \text{ W} @ V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 0.040 \text{ W} @ V_{GS} = -2.5 \text{ V}$
- High density cell design for extremely low R_{DS(ON)}.
- Small footprint (38% smaller than a standard SO-8); low profile package (1 mm thick); power handling capability similar to SO-8.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		<u>±</u> 8	V
I_D	Drain Current - Continuous	(Note 1a)	-6.1	А
	- Pulsed		-18	
P _D	Power Dissipation for Single Operation	(Note 1a)	1.8	W
		(Note 1b)	1.0	
		(Note 1c)	0.9	
T _J , T _{stg}	Operating and Storage Junction Temperatur	-55 to +150	°C	

Thermal Characteristics

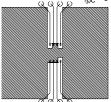
$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	70	∘C/W
R _{AJC}	Thermal Resistance, Junction-to-Case	(Note 1)	20	°C/W

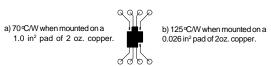
Package Outlines and Ordering Information

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Device Marking	Device	Reel Size	Tape Width	Quantity	
.836P	FDR836P	13"	12mm	3000 units	

Symbol	Parameter	Min	Тур	Max	Units	
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
∆BVbss ∆TJ	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-24		mV/∘C
DSS	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μА
GSSF	Gate-Body Leakage Current, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
GSSR	Gate-Body Leakage Current, Reverse	V _{GS} = -8 V, V _{DS} = 0 V			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-0.6	-1	V
ΔVGS(th) ΔT _J	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μA, Referenced to 25°C		3		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -6.1 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -6.1 \text{ A}, T_J = 125 ^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -5 \text{ A}$		0.022 0.031 0.029	0.030 0.048 0.040	Ω
D(on)	On-State Drain Current	V _{GS} = -4.5 V, V _{DS} = -5 V	-9			Α
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -6.1 \text{A}$		22		S
Dynamic	Characteristics				•	•
C _{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$		2200		pF
Coss	Output Capacitance	f = 1.0 MHz		570		pF
C _{rss}	Reverse Transfer Capacitance			140		pF
Switchin	g Characteristics (Note 2)	,		!		
t _{d(on)}	Turn-On Delay Time	V _{DD} = -10 V. I _D = -1 A.		10	18	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		14	25	ns
d(off)	Turn-Off Delay Time			225	360	ns
-(<i>)</i>	Turn-Off Fall Time			85	135	ns
Q_g	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -6.1 \text{ A},$		32	44	nC
Q _{qs}	Gate-Source Charge	V _{GS} = - 4.5 V		3.2		nC
Q_{gd}	Gate-Drain Charge	1		8.1		nC
_	ourse Diede Cheresteristics an	d Maximum Datings		•		
<u>Drain-Sc</u> s	Durce Diode Characteristics and Maximum Continuous Drain-Source Dio	_			-1.5	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -1.5 \text{ A}$ (Note 2)		-0.65	-1.2	V

1. R_{QJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain Pins. R_{QIC} is guaranteed by design while R_{QCA} is determined by the user's board design.







c) 135 C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width £ 300 ms, Duty Cycle £ 2.0%

Typical Characteristics

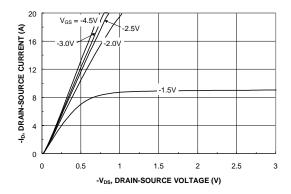


Figure 1. On-Region Characteristics.

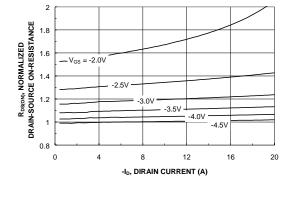


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

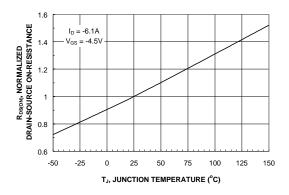


Figure 3. On-Resistance Variation with Temperature.

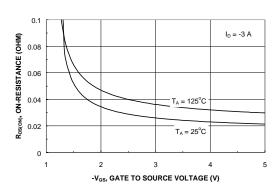


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

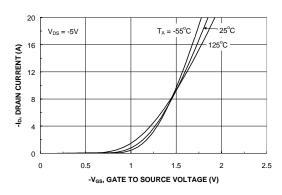


Figure 5. Transfer Characteristics.

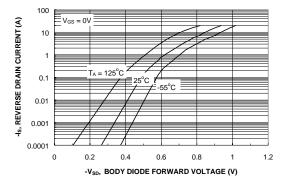
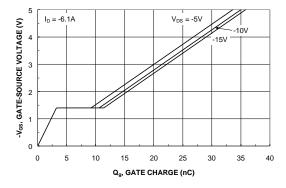


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



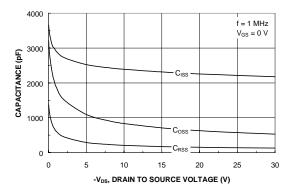


Figure 7. Gate-Charge Characteristics.

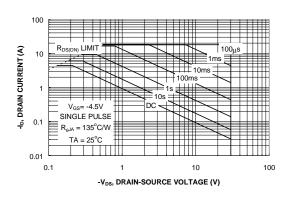


Figure 8. Capacitance Characteristics.

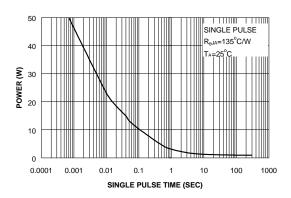


Figure 9. Maximum Safe Operating Area.



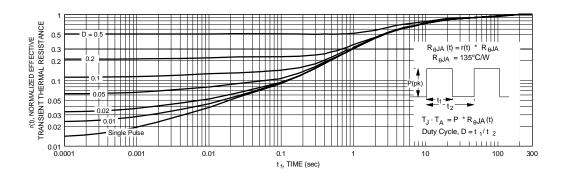
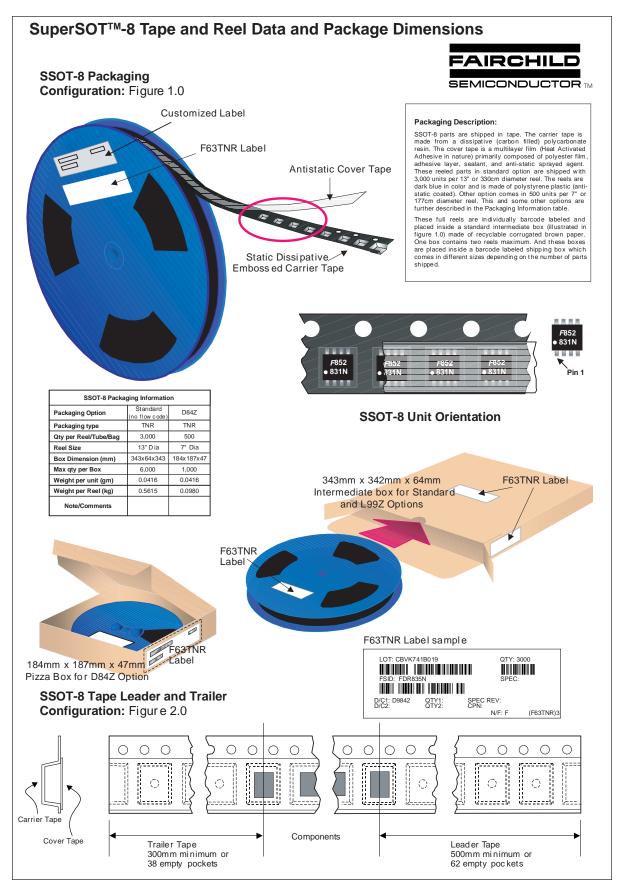
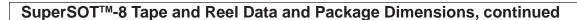


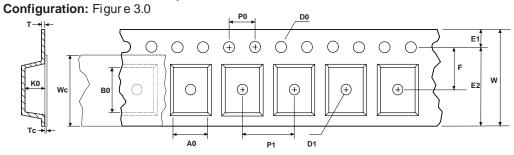
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.





SSOT-8 Embossed Carrier Tape



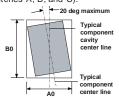


	Dimensions are in millimeter													
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	Т	Wc	Тс
SSOT-8 (12mm)	4.47 +/-0.10	5.00 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.280 +/-0.150	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation

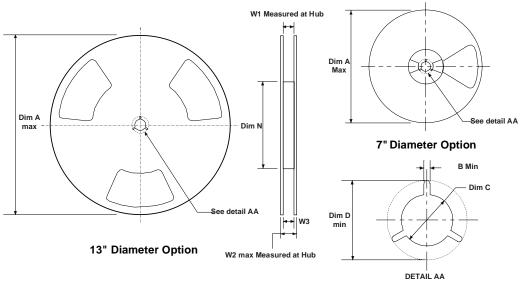


Sketch B (Top View)
Component Rotation



Sketch C (Top View)
Component lateral movement

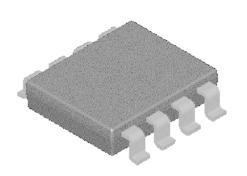
SSOT-8 Reel Configuration: Figur e 4.0

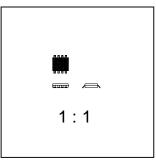


	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

SuperSOT™-8 Tape and Reel Data and Package Dimensions, continued

SuperSOT™-8 (FS PKG Code 34, 35)

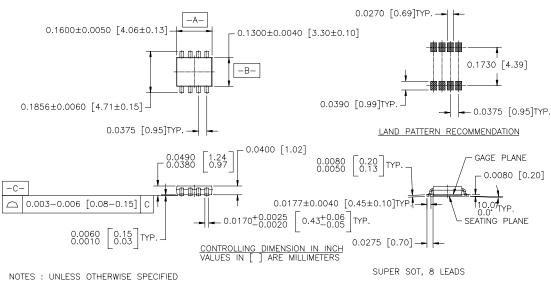




Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.0416



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2. NO JEDEC REGISTRATION AS JAN. 1996

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